

Title (en)  
DYNAMIC STRUCTURAL COUPLING MECHANISM FOR REDUCING OPTICAL DEGRADATION IN VIBRATING ENVIRONMENTS

Title (de)  
DYNAMISCHER STRUKTURELLER KUPPLUNGSMECHANISMUS ZUR VERMINDERUNG DER OPTISCHEN DEGRADIERUNG IN SCHWINGENDEN UMGEBUNGEN

Title (fr)  
MECANISME DE COUPLAGE DYNAMIQUE STRUCTUREL POUR LA REDUCTION DE LA DEGRADATION OPTIQUE DANS DES ENVIRONNEMENTS VIBRANTS

Publication  
**EP 1095515 A2 20010502 (EN)**

Application  
**EP 00908332 A 20000120**

Priority  
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• US 44902399 A 19991124

Abstract (en)  
[origin: WO0048232A2] Vibration damping apparatus for vibrating environment such as a light emission microscope and an integrated circuit test head includes a rigid member with remotely controlled clamping means attached to spaced portions of the member. The clamping means engage the microscope and the test head for reducing vibrations, and the clamping means can be readily deactivated for moving the microscope or the test head for alignment purposes. Advantageously, two or more rigid members including pneumatic cylinders can be positioned around the device under test while permitting the use of mechanical probes for engaging nodes of an integrated circuit for test purposes.

[origin: WO0048232A2] Vibration damping apparatus for vibrating environment such as a light emission microscope (60) and integrated circuit test head (56) includes a rigid member (40) with remotely controlled clamping means attached to spaced portions of the member. The clamping means engage the microscope and the test head for reducing vibrations, and the clamping means can be readily deactivated for moving the microscope or the test head for alignment purposes. Advantageously, two or more rigid members including pneumatic cylinders (52) can be positioned around the device under test while permitting the use of mechanical probes for engaging nodes of an integrated circuit for test purposes.

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IPC 8 full level  
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See references of WO 0048232A2

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